

12500 TI Boulevard, MS 8640, Dallas, Texas 75243

PCN# 20150511000 Qualification of NSE as Additional Assembly Site for Select VQFN package device Change Notification / Sample Request

Date: 5/14/2015

To: Newark/Farnell PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The changes discussed within this PCN will not take effect any earlier than **90** days from the date of this notification, unless customer agreement has been reached on an earlier implementation of the change. This notification period is per TI's standard process.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (PCN www admin team@list.ti.com).

Sincerely,

PCN Team SC Business Services

20150511000 Attachment: 1

Products Affected:

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

DEVICE CC1101RGPR CC1101RGP **CUSTOMER PART NUMBER**

null null

Technical details of this Product Change follow on the next page(s).

PCN Number:		20150511000					PCN Date:	05/14/2015		
Title:	Qualification	of NS	E as Addi	itional <i>i</i>	Assembly S	Site for Sel	ect \	/QFN packag	e device	
Customer	Contact:	PCN A	<u>Nanager</u>	Dept	t:	Quality S	ervi	ces		
Proposed 1 st Ship Date		e:			Estimated Sample A		. Av	ailability:	Date Provided at Sample request	
Change T	уре:									
_	nbly Site	,			Design			Wafer Bump Site		
	nbly Process					Wafer Bum	•			
	nbly Materials		Part number change Wafer Bump Pro			•				
	nical Specifica				Site		Н	Wafer Fab Site		
Packir	ng/Shipping/La	ibeling	9 _	lest	Process		Н	Wafer Fab Materials Wafer Fab Process		
				DC	N Detail		Ш	water Fab	Process	
Description	on of Change	•		PC	ii Detaii	3				
Description of Change: Qualification of NSE as Additional Assembly Site for Select VQFN package device. Assembly differences are shown in the following table:										
			TI Clark				NSE			
Mount Co	mpound				7123			PZ0031		
Wire			42:		(0.8 Mil Cu)	G	GZ0017 (1.0 Mil Au)		
Lead finis	sh			NiPdAu				NiPdAuAg		
Reason fo	or Change:									
Continuity	of Supply									
Anticipate	ed impact on	Form	n, Fit, Fu	nction	, Quality	or Reliabi	lity	(positive /	negative):	
None										
Changes	to product id	- 141								
	to product id	entifi	ication r	esultir	ng from th	is PCN:				
Assembl		entifi	ication r	esultir	ng from th	is PCN:				
Assembl TI Clark	y Site	entifi						ASO: 0	QAB	
	y Site Philippines	entifi	Ass	sembly	Site Origin	n (22L)		ASO: (•	
TI Clark NSE Tha	y Site Philippines		As:	sembly sembly	Site Origir Site Origir	n (22L) n (22L)			•	
TI Clark NSE Tha Sample p TEXA INSTRUM MADE IN: 2DC: MSL '2 /26 MSL '2 /26 MSL 1 /25 OPT: ITEM:	y Site Philippines iland roduct shippin	g labe	As:	sembly sembly	Site Origin Site Origin Product lab (1P) \$N7 (Q) 200 (31T) LOT (4W) TKY	(22L) (22L) (22L) (1) (22L) (1) (20) (1) (1) (20) (1) (20) (1) (20) (1) (20) (20) (20) (20) (20) (20) (20) (20	7MLA 483 00333 000:0	ASO: I	•	
TI Clark NSE Tha Sample p TEXA INSTRUM MADE IN: 20C: MSL 2 /26 MSL 1 /23 OPT: ITEM: LBL: 5	y Site Philippines iland roduct shippin AS HENTS Malaysia 20: 50C/1 YEAR SEAL 35C/UNLIM 03/25	g labe	As: As:	sembly sembly actual p	Site Origin Site Origin Site Origin Oroduct lab (1P) \$N7 (Q) 200 (31T)L01 (4W) TKY (P) (2P) REV: (20L) CSO: (22L) ASO:	(22L) (22L) (22L) (1) (22L) (1) (20) (1) (1) (20) (1) (20) (1) (20) (1) (20) (20) (20) (20) (20) (20) (20) (20	7MLA 483 00333 000:0	ASO: I	•	

CC1101RGPT

CC1101RGP

CC1101RGPR

TLMW301RGPR

Qualification Report

Product Attributes

Attributes	Qual Device: CC1101RGP	Supporting QBS: TLV320AlC3254RHB	Supporting QBS: CC1101RGP
Assembly Site	UTAC/NSE	UTAC/NSE	UTAC/NSE
Package Family	QFN	QFN	QFN
Flammability Rating	UL 94 V-0	UL 94 V-0	UL94V-0
Die Attributes			
Wafer Fab Site	TSMC FAB 4	DMOS5	TSMC FAB 4
Wafer Fab Process	0.18UM-TSMC	1833C05	0.18UM-TSMC
Package Attributes			
Package Designator	RGP	RHB	RGP
Package Size (mils)	157.48 X 157.48	196.85 X 196.85	157.48 X 157.48
Body Thickness (mils)	39.37	35.43	39.37
Pin Count	20	32	20
Lead Frame Material	Cu	Cu	Cu
Lead Finish	NiPdAuAg	NiPdAu	NiPdAu
Mount Compound	PZ0031	PZ0031	PZ0031
Mold Compound	CZ0142	CZ0142	CZ0142
Green Status	Qualified Pb-free(SMT) and Green	Qualified Pb-free(SMT) and Green	Qualified Pb-free(SMT) and Green
Bond Wire Composition	Au	Au	Au
Bond Wire Diameter (mils)	1.0	1.0	1.0
Flammability Rating	UL 94 V-0	UL 94 V-0	UL94V-0

⁻ QBS: Qual By Similarity

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: CC1101RGP	Supporting QBS: TLV320AlC3254RHB	Supporting QBS: CC1101RGP
AC	Autoclave	121C, 100%RH/96 hours	-	-	1/75/0
TC	Temperature Cycle	-65/150C/500 cycles	-	-	1/77/0
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	3/3/0	-	-
MSL	Moisture Sensitivity, JEDEC	Level 3-260C	3/36/0	1/12/0	-

⁻ Preconditioning was performed for Autoclave, Temperature Cycle, as applicable

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com

⁻ Qual Device CC1101RGP is qualified at LEVEL3-260C